Supporting Information

Host and guest joining forces: a holistic approach for metal-organic frameworks in nonlinear optics

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<u>1. Structure of MOF-177</u>



Figure S1. Structure of MOF-177.^{1,2}



2. FT-IR spectra obtained from C₆₀⊂MOF-177, Li@C₆₀⊂MOF-177 and precursor compounds

Figure S2. FTIR obtained from toluene (grey), $C_{60} \subset$ MOF-177 (pink), MOF-177 (black), Li@C₆₀ \subset MOF-177 (red), Li⁺@C₆₀(PF₆⁻) powder (blue), oDCB (green) and ACN (orange).

<u>3. ICP-OES measurement for lithium</u>



Figure S3. ICP-OES result of lithium after digesting Li@C₆₀ \subset MOF-177. ICP emission from Li was observed at 610.364 nm.

4. Thermogravimetry for determination of Li@C60 loading



Figure S4. Thermogravimetry of $Li@C_{60} \subset MOF-177$ (red), MOF-177 (black solid) and $Li@C_{60}[PF_6]$ (black dots).

5. Raman spectrum of Li@C60 in solution of oDCB and ACN



Figure S5. Raman spectrum of Li@C₆₀ dissolved in a 1:1 (v:v) mixture of oDCB and ACN. The $A_g(2)$ mode of peak of C₆₀ can still be observed.



6. Raman spectrum of C₆₀⊂MOF-177

Figure S6. Raman spectrum obtained from C_{60} ⊂MOF-177. The $A_g(2)$ mode of C_{60} can be clearly observed. Excited by 785 nm laser.



7. Raman spectra obtained for analysis of Zn-O bond of MOF-177

Figure S7. Raman spectra obtained from MOF-177 (a) soaked in odichlorobenzene/acetonitrile, (b) with accommodated C_{60} and (c) with accommodated $Li@C_{60}$. The orange line shows the background that was substracted.



8. Raman mapping obtained from C₆₀⊂MOF-177 and Li@C₆₀⊂MOF-177

Figure S8. Raman scattering intensity x,y map of (a) C_{60} \subset MOF-177 and (b) Li@C_{60} \subset MOF-177. (c) schematic illustration to indicate z-position for the depth direction. Raman scattering intensity along the depth direction of (d) C_{60} \subset MOF-177 and (e) Li@C_{60} \subset MOF-177. The relative intensity of C₆₀ (1470 cm⁻¹) against MOF-177 (1610 cm⁻¹) and Li@C_{60} (272 cm⁻¹) against MOF-177 (1360cm⁻¹) were plotted for C₆₀ \subset MOF-177 and Li@C_{60} \subset MOF-177, respectively. Scale bars are 2 µm.

9. UV-vis spectrum of Li@C₆₀ dissolved in 1:1 (v:v) mixture of o-dichlorobenzene and <u>acetonitrile</u>



Figure S9. UV-vis spectrum of $Li@C_{60}$ dissolved in 1:1 (v:v) mixture of o-dichlorobenzene and acetonitrile

10. SHG from MOF-177 after exposure to vacuum



Figure S10. SHG from MOF-177 after exposure to vacuum for 30 min.

<u>11. Correction of the polarized SHG data</u>



Figure S11. SHG from a C_{60} films while the polarization of the excitation beam is rotated. Excitation by 830 nm.

Several components of the microscope as well as the detection system have a polarization dependence (e.g. dichroic mirrors, grating, ...). In order to account for these dependences, a C_{60} film was used. It was reported previously that the SHG emission from C_{60} films remains constant when the polarization of the excitation beam is rotated.³

The SHG intensity emitted from a C_{60} film upon rotation of the polarization is shown in Figure S6. The resulting data has been fitted using a cosine function. The resulting function was then normalized and the experimental data obtained from MOF-177 divided by this normalized curve to obtain the corrected data.



Figure S12. Photographs of (a) C_{60} \subset MOF-177 and (b) Li@C₆₀ \subset MOF-177.

References

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